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### Contact us

Tel: +86-755-8981 8866 Fax: +86-755-8427 6832 Email & Skype: info@chipsmall.com Web: www.chipsmall.com Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China





### LTC2430/LTC2431

CHNOLOGY 20-Bit No Latency ∆∑<sup>™</sup> ADCs with Differential Input and Differential Reference

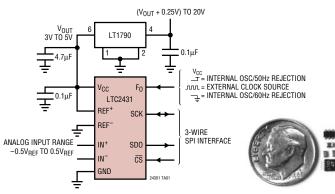
### FEATURES

- Low Supply Current (200µA in Conversion Mode and 4µA in Autosleep Mode)
- Differential Input and Differential Reference with GND to V<sub>CC</sub> Common Mode Range
- 3ppm INL, No Missing Codes
- IOppm Full-Scale Error and Ippm Offset
- 0.56ppm Noise, 20.8 ENOBs
- No Latency: Digital Filter Settles in a Single Cycle. Each Conversion Is Accurate, Even After an Input Step
- Single Supply 2.7V to 5.5V Operation
- Internal Oscillator—No External Components Required
- 110dB Min, 50Hz/60Hz Notch Filter
- Pin Compatible with 24-Bit LTC2410/LTC2411

### **APPLICATIONS**

- Direct Sensor Digitizer
- Weight Scales
- Direct Temperature Measurement
- Gas Analyzers
- Strain Gauge Transducers
- Instrumentation
- Data Acquisition
- Industrial Process Control
- DVMs and Meters

### TYPICAL APPLICATIONS



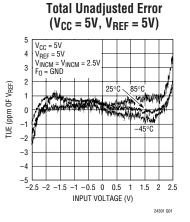


The LTC<sup>®</sup>2430/LTC2431 are 2.7V to 5.5V micropower 20-bit differential  $\Delta\Sigma$  analog-to-digital converters with an integrated oscillator, 3ppm INL and 0.56ppm RMS noise. They use delta-sigma technology and provide single cycle settling time for multiplexed applications. Through a single pin, the LTC2430/LTC2431 can be configured for better than 110dB differential mode rejection at 50Hz or 60Hz ±2%, or they can be driven by an external oscillator for a user-defined rejection frequency. The internal oscillator requires no external frequency setting components.

The converters accept any external differential reference voltage from 0.1V to  $V_{CC}$  for flexible ratiometric and remote sensing measurement configurations. The full-scale differential input range is from  $-0.5V_{REF}$  to  $0.5V_{REF}$ . The reference common mode voltage,  $V_{REFCM}$ , and the input common mode voltage,  $V_{INCM}$ , may be independently set anywhere within GND to  $V_{CC}$ . The DC common mode input rejection is better than 120dB.

The LTC2430/LTC2431 communicate through a flexible 3-wire digital interface that is compatible with SPI and MICROWIRE<sup>TM</sup> protocols.

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### ABSOLUTE MAXIMUM RATINGS (Notes 1, 2)

Supply Voltage (V <sub>CC</sub> ) to GND0.3V to 7V Analog Input Pins Voltage	Digit Oper
to $GND$	Ĺ
Reference Input Pins Voltage	Ľ
to GND $-0.3V$ to (V <sub>CC</sub> + 0.3V)	Stor
Digital Input Voltage to GND $-0.3V$ to (V <sub>CC</sub> + 0.3V)	Leac

Digital Output Voltage to GND0.3	V to (V <sub>CC</sub> + 0.3V)
Operating Temperature Range	
LTC2430C/LTC2431C	0°C to 70°C
LTC2430I/LTC2431I	−40°C to 85°C
Storage Temperature Range	. −65°C to 150°C
Lead Temperature (Soldering, 10 sec)	300°C

### PACKAGE/ORDER INFORMATION

TOP	/IEW	ORDER PART NUMBER		ORDER PART NUMBER
$\begin{array}{c c} \text{GND} & \boxed{1} \\ V_{\text{CC}} & \boxed{2} \\ \text{REF}^+ & \boxed{3} \\ \text{REF}^- & \boxed{4} \\ \text{IN}^+ & \boxed{5} \end{array}$	16 GND 15 GND 14 F <sub>0</sub> 13 SCK 12 SD0	LTC2430CGN LTC2430IGN	TOP VIEW V <sub>CC</sub> 1 0 - 10 F <sub>0</sub> REF <sup>+</sup> 2 0 9 SCK REF <sup>-</sup> 3 0 8 SD0 IN <sup>+</sup> 4 0 7 CS	LTC2431CMS LTC2431IMS
	11 CS	GN PART MARKING	IN <sup>−</sup> 5 MS PACKAGE	MS PART MARKING
GND 7 GND 8 GN PAL 16-LEAD PL T <sub>JMAX</sub> = 125°C,	ASTIC SSOP	2430 2430I	10-LEAD PLASTIC MSOP $T_{JMAX} = 125^{\circ}C, \theta_{JA} = 120^{\circ}C/W$	LTXD LTXE

Consult LTC Marketing for parts specified with wider operating temperature ranges.

# **ELECTRICAL CHARACTERISTICS** The $\bullet$ denotes specifications which apply over the full operating temperature range, otherwise specifications are at T<sub>A</sub> = 25°C. (Notes 3, 4)

PARAMETER	CONDITIONS		MIN	ТҮР	MAX	UNITS
Resolution (No Missing Codes)	$0.1V \le V_{REF} \le V_{CC}, -0.5 \bullet V_{REF} \le V_{IN} \le 0.5 \bullet V_{REF}$ (Note 5)		20			Bits
Integral Nonlinearity	$\begin{array}{l} 4.5V \leq V_{CC} \leq 5.5V, \ REF^+ = 2.5V, \ REF^- = GND, \ V_{INCM} = 1.25V \ (Note \ 6) \\ 5V \leq V_{CC} \leq 5.5V, \ REF^+ = 5V, \ REF^- = GND, \ V_{INCM} = 2.5V \ (Note \ 6) \\ REF^+ = 2.5V, \ REF^- = GND, \ V_{INCM} = 1.25V \ (Note \ 6) \end{array}$	•		2 3 10	20	ppm of V <sub>REF</sub> ppm of V <sub>REF</sub> ppm of V <sub>REF</sub>
Offset Error	$2.5V \le REF^+ \le V_{CC}$ , $REF^- = GND$ , GND $\le IN^+ = IN^- \le V_{CC}$ (Note 14)	•		5	20	μV
Offset Error Drift	$2.5V \le REF^+ \le V_{CC}$ , $REF^- = GND$ , GND $\le IN^+ = IN^- \le V_{CC}$			50		nV/°C
Positive Full-Scale Error	$2.5V \le REF^+ \le V_{CC}, REF^- = GND,$ IN <sup>+</sup> = 0.75REF <sup>+</sup> , IN <sup>-</sup> = 0.25 • REF <sup>+</sup>	•		10	20	ppm of V <sub>REF</sub>
Positive Full-Scale Error Drift	$2.5V \le REF^+ \le V_{CC}, REF^- = GND,$ IN <sup>+</sup> = 0.75REF <sup>+</sup> , IN <sup>-</sup> = 0.25 • REF <sup>+</sup>			0.1		ppm of V <sub>REF</sub> /°C
Negative Full-Scale Error	$2.5V \le REF^+ \le V_{CC}$ , $REF^- = GND$ , $IN^+ = 0.25 \bullet REF^+$ , $IN^- = 0.75 \bullet REF^+$	•		10	20	ppm of V <sub>REF</sub>
Negative Full-Scale Error Drift	$2.5V \le \text{REF}^+ \le V_{CC}$ , $\text{REF}^- = \text{GND}$ , IN <sup>+</sup> = 0.25 • $\text{REF}^+$ , IN <sup>-</sup> = 0.75 • $\text{REF}^+$			0.1		ppm of V <sub>REF</sub> /°C
Total Unadjusted Error	$\begin{array}{l} 4.5V \leq V_{CC} \leq 5.5V, \ REF^+ = 2.5V, \ REF^- = GND, \ V_{INCM} = 1.25V \\ 5V \leq V_{CC} \leq 5.5V, \ REF^+ = 5V, \ REF^- = GND, \ V_{INCM} = 2.5V \\ REF^+ = 2.5V, \ REF^- = GND, \ V_{INCM} = 1.25V \end{array}$			3 6 15		ppm of V <sub>REF</sub> ppm of V <sub>REF</sub> ppm of V <sub>REF</sub>
Output Noise	$ \begin{array}{l} 5V \leq V_{CC} \leq 5.5V, \ REF^+ = 5V, \ V_{REF}^- = GND, \\ GND \leq IN^- = IN^+ \leq 5V, \ (Note \ 13) \end{array} $			2.8		μV <sub>RMS</sub>
						24301f



# **CONVERTER CHARACTERISTICS** The $\bullet$ denotes specifications which apply over the full operating temperature range, otherwise specifications are at T<sub>A</sub> = 25°C. (Notes 3, 4)

PARAMETER	CONDITIONS		MIN	ТҮР	MAX	UNITS
Input Common Mode Rejection DC	$\begin{array}{l} 2.5V \leq REF^+ \leq V_{CC}, \ REF^- = GND, \\ GND \leq IN^- = IN^+ \leq 5V \ (Note \ 5) \end{array}$	•	110	120		dB
Input Common Mode Rejection 60Hz $\pm 2\%$	$\begin{array}{l} 2.5V \leq REF^+ \leq V_{CC}, \ REF^- = GND, \\ GND \leq IN^- = IN^+ \leq 5V, \ (Notes \ 5, \ 7) \end{array}$	•	140			dB
Input Common Mode Rejection 50Hz $\pm 2\%$	$\begin{array}{l} 2.5V \leq REF^+ \leq V_{CC}, \ REF^- = GND, \\ GND \leq IN^- = IN^+ \leq 5V, \ (Notes \ 5, \ 8) \end{array}$	•	140			dB
Input Normal Mode Rejection 60Hz ±2%	(Notes 5, 7)	•	110	140		dB
Input Normal Mode Rejection 50Hz ±2%	(Notes 5, 8)	•	110	140		dB
Reference Common Mode Rejection DC	$2.5V \le REF^+ \le V_{CC}$ , $GND \le REF^- \le 2.5V$ , $V_{REF} = 2.5V$ , $IN^- = IN^+ = GND$ (Note 5)	•	130	140		dB
Power Supply Rejection, DC	$REF^+ = 2.5V, REF^- = GND, IN^- = IN^+ = GND$			110		dB
Power Supply Rejection, $60Hz \pm 2\%$	$REF^+ = 2.5V, REF^- = GND, IN^- = IN^+ = GND, (Note 7)$			120		dB
Power Supply Rejection, 50Hz $\pm 2\%$	$REF^+ = 2.5V, REF^- = GND, IN^- = IN^+ = GND, (Note 8)$			120		dB

**ANALOG INPUT AND REFERENCE** The  $\bullet$  denotes specifications which apply over the full operating temperature range, otherwise specifications are at T<sub>A</sub> = 25°C. (Note 3)

SYMBOL	PARAMETER	CONDITIONS		MIN	ТҮР	MAX	UNITS
IN <sup>+</sup>	Absolute/Common Mode IN <sup>+</sup> Voltage		•	GND – 0.3V		V <sub>CC</sub> + 0.3V	V
IN <sup>-</sup>	Absolute/Common Mode IN <sup>-</sup> Voltage		•	GND – 0.3V		V <sub>CC</sub> + 0.3V	V
V <sub>IN</sub>	Input Differential Voltage Range (IN <sup>+</sup> – IN <sup>-</sup> )		•	-V <sub>REF</sub> /2		V <sub>REF</sub> /2	V
REF <sup>+</sup>	Absolute/Common Mode REF <sup>+</sup> Voltage		•	0.1		V <sub>CC</sub>	V
REF <sup>-</sup>	Absolute/Common Mode REF <sup>-</sup> Voltage		•	GND		$V_{CC} - 0.1V$	V
V <sub>REF</sub>	Reference Differential Voltage Range (REF <sup>+</sup> – REF <sup>-</sup> )		•	0.1		V <sub>CC</sub>	V
C <sub>S</sub> (IN <sup>+</sup> )	IN <sup>+</sup> Sampling Capacitance				1.5		pF
C <sub>S</sub> (IN <sup>-</sup> )	IN <sup>-</sup> Sampling Capacitance				1.5		pF
C <sub>S</sub> (REF <sup>+</sup> )	REF <sup>+</sup> Sampling Capacitance				1.5		pF
C <sub>S</sub> (REF <sup>-</sup> )	REF <sup>-</sup> Sampling Capacitance				1.5		pF
I <sub>DC_LEAK</sub> (IN+)	IN <sup>+</sup> DC Leakage Current	$\overline{\text{CS}} = \text{V}_{\text{CC}}, \text{ IN}^+ = \text{GND}$	•	-10	1	10	nA
I <sub>DC_LEAK</sub> (IN <sup>-</sup> )	IN <sup>-</sup> DC Leakage Current	$\overline{\text{CS}} = \text{V}_{\text{CC}}, \text{ IN}^- = \text{V}_{\text{CC}}$	•	-10	1	10	nA
I <sub>DC_LEAK</sub> (REF <sup>+</sup> )	REF <sup>+</sup> DC Leakage Current	$\overline{\text{CS}} = \text{V}_{\text{CC}}, \text{REF}^+ = \text{V}_{\text{CC}}$	•	-10	1	10	nA
I <sub>DC_LEAK</sub> (REF <sup>-</sup> )	REF <sup>-</sup> DC Leakage Current	$\overline{\text{CS}} = \text{V}_{\text{CC}}, \text{REF}^- = \text{GND}$	•	-10	1	10	nA

# **DIGITAL INPUTS AND DIGITAL OUTPUTS** The $\bullet$ denotes specifications which apply over the full operating temperature range, otherwise specifications are at T<sub>A</sub> = 25°C. (Note 3)

SYMBOL	PARAMETER	CONDITIONS		MIN	ТҮР	MAX	UNITS
V <sub>IH</sub>	High Level Input Voltage CS, F <sub>0</sub>	$\begin{array}{c} 2.7V \leq V_{CC} \leq 5.5V \\ 2.7V \leq V_{CC} \leq 3.3V \end{array}$	•	2.5 2.0			V V
V <sub>IL</sub>	Low Level Input Voltage $\overline{\text{CS}}$ , $\text{F}_0$	$\begin{array}{l} 4.5V \leq V_{CC} \leq 5.5V \\ 2.7V \leq V_{CC} \leq 5.5V \end{array}$	•			0.8 0.6	V V
V <sub>IH</sub>	High Level Input Voltage SCK	$\begin{array}{c} 2.7V \leq V_{CC} \leq 5.5V \; (\text{Note 9}) \\ 2.7V \leq V_{CC} \leq 3.3V \; (\text{Note 9}) \end{array}$	•	2.5 2.0			V V
VIL	Low Level Input Voltage SCK	$\begin{array}{c} 4.5V \leq V_{CC} \leq 5.5V \; (Note \; 9) \\ 2.7V \leq V_{CC} \leq 5.5V \; (Note \; 9) \end{array}$	•			0.8 0.6	V V
I <sub>IN</sub>	Digital Input Current CS, F <sub>0</sub>	$0V \le V_{IN} \le V_{CC}$	•	-10		10	μΑ
I <sub>IN</sub>	Digital Input Current SCK	$0V \le V_{IN} \le V_{CC}$ (Note 9)	•	-10		10	μΑ
C <sub>IN</sub>	Digital Input Capacitance CS, F <sub>0</sub>				10		pF
C <sub>IN</sub>	Digital Input Capacitance SCK	(Note 9)			10		pF
V <sub>OH</sub>	High Level Output Voltage SDO	$I_0 = -800 \mu A$	•	V <sub>CC</sub> – 0.5V			V
V <sub>OL</sub>	Low Level Output Voltage SDO	I <sub>0</sub> = 1.6mA	•			0.4	V
V <sub>OH</sub>	High Level Output Voltage SCK	I <sub>0</sub> = -800μA (Note 10)	•	V <sub>CC</sub> – 0.5V			V
V <sub>OL</sub>	Low Level Output Voltage SCK	I <sub>0</sub> = 1.6mA (Note 10)	•			0.4	V
I <sub>OZ</sub>	Hi-Z Output Leakage SDO		•	-10		10	μA

# **POWER REQUIREMENTS** The $\bullet$ denotes specifications which apply over the full operating temperature range, otherwise specifications are at T<sub>A</sub> = 25°C. (Note 3)

SYMBOL	PARAMETER	CONDITIONS		MIN	ТҮР	MAX	UNITS
V <sub>CC</sub>	Supply Voltage		•	2.7		5.5	V
Icc	Supply Current Conversion Mode Sleep Mode Sleep Mode	$\label{eq:constraint} \begin{array}{c} \overline{CS} = 0V \mbox{ (Note 12)} \\ \overline{CS} = V_{CC} \mbox{ (Note 12)} \\ \overline{CS} = V_{CC}, 2.7V \leq V_{CC} \leq 3.3V \\ \mbox{ (Note 12)} \end{array}$	•		200 4 2	300 10	μΑ μΑ μΑ



TIMING CHARACTERISTICS The • denotes specifications which apply over the full operating temperature range, otherwise specifications are at  $T_A = 25^{\circ}C$ . (Note 3)

SYMBOL	PARAMETER	CONDITIONS		MIN	ТҮР	MAX	UNITS
f <sub>EOSC</sub>	External Oscillator Frequency Range			5		2000	kHz
t <sub>HEO</sub>	External Oscillator High Period		•	0.25		200	μs
t <sub>LEO</sub>	External Oscillator Low Period		•	0.25		200	μs
t <sub>CONV</sub>	Conversion Time	$F_0 = 0V$ $F_0 = V_{CC}$ External Oscillator (Note 11)	•	130.86 157.03 205	133.53 160.23 510/f <sub>EOSC</sub> (in	136.20 163.44 kHz)	ms ms ms
f <sub>ISCK</sub>	Internal SCK Frequency	Internal Oscillator (Note 10) External Oscillator (Notes 10, 11)			19.2 f <sub>EOSC</sub> /8		kHz kHz
D <sub>ISCK</sub>	Internal SCK Duty Cycle	(Note 10)	•	45		55	%
f <sub>ESCK</sub>	External SCK Frequency Range	(Note 9)	•			2000	kHz
t <sub>LESCK</sub>	External SCK Low Period	(Note 9)		250			ns
t <sub>HESCK</sub>	External SCK High Period	(Note 9)		250			ns
t <sub>dout_isck</sub>	Internal SCK 24-Bit Data Output Time	Internal Oscillator (Notes 10, 12) External Oscillator (Notes 10, 11)	•	1.22 19	1.25 92/f <sub>EOSC</sub> (in k	1.28 (Hz)	ms ms
t <sub>DOUT_ESCK</sub>	External SCK 24-Bit Data Output Time	(Note 9)		2	4/f <sub>ESCK</sub> (in kł	Hz)	ms
t <sub>1</sub>	$\overline{CS} \downarrow$ to SDO Low Z			0		200	ns
t <sub>2</sub>	$\overline{\text{CS}} \uparrow$ to SDO High Z		•	0		200	ns
t <sub>3</sub>	$\overline{\text{CS}} \downarrow \text{to SCK} \downarrow$	(Note 10)	•	0		200	ns
t <sub>4</sub>	$\overline{\text{CS}} \downarrow \text{to SCK} \uparrow$	(Note 9)	•	50			ns
t <sub>KQMAX</sub>	SCK $\downarrow$ to SDO Valid					220	ns
t <sub>kqmin</sub>	SDO Hold After SCK $\downarrow$	(Note 5)		15			ns
t <sub>5</sub>	SCK Set-Up Before $\overline{\text{CS}}\downarrow$			50			ns
t <sub>6</sub>	SCK Hold After $\overline{\text{CS}}\downarrow$					50	ns

Note 1: Absolute Maximum Ratings are those values beyond which the life of the device may be impaired.

Note 2: All voltage values are with respect to GND.

Note 3:  $V_{CC} = 2.7V$  to 5.5V unless otherwise specified.

$$\begin{split} & \mathsf{V}_{\mathsf{REF}} = \mathsf{REF}^+ - \mathsf{REF}^-, \, \mathsf{V}_{\mathsf{REFCM}} = (\mathsf{REF}^+ + \mathsf{REF}^-)/2; \\ & \mathsf{V}_{\mathsf{IN}} = \mathsf{IN}^+ - \mathsf{IN}^-, \, \mathsf{V}_{\mathsf{INCM}} = (\mathsf{IN}^+ + \mathsf{IN}^-)/2. \end{split}$$

Note 4: F<sub>0</sub> pin tied to GND or to V<sub>CC</sub> or to external conversion clock source with  $f_{EOSC} = 153600$ Hz unless otherwise specified.

Note 5: Guaranteed by design, not subject to test.

Note 6: Integral nonlinearity is defined as the deviation of a code from a straight line passing through the actual endpoints of the transfer curve. The deviation is calculated as the measured code minus the expected value.

Note 7:  $F_0 = 0V$  (internal oscillator) or  $f_{EOSC} = 153600$ Hz  $\pm 2\%$ (external oscillator).

Note 8:  $F_0 = V_{CC}$  (internal oscillator) or  $f_{EOSC} = 128000$  Hz  $\pm 2\%$ (external oscillator).

Note 9: The converter is in external SCK mode of operation such that the SCK pin is used as digital input. The frequency of the clock signal driving SCK during the data output is f<sub>ESCK</sub> and is expressed in kHz.

Note 10: The converter is in internal SCK mode of operation such that the SCK pin is used as digital output. In this mode of operation the SCK pin has a total equivalent load capacitance  $C_{LOAD} = 20 pF$ .

**Note 11:** The external oscillator is connected to the  $F_0$  pin. The external oscillator frequency, f<sub>FOSC</sub>, is expressed in kHz.

Note 12: The converter uses the internal oscillator.

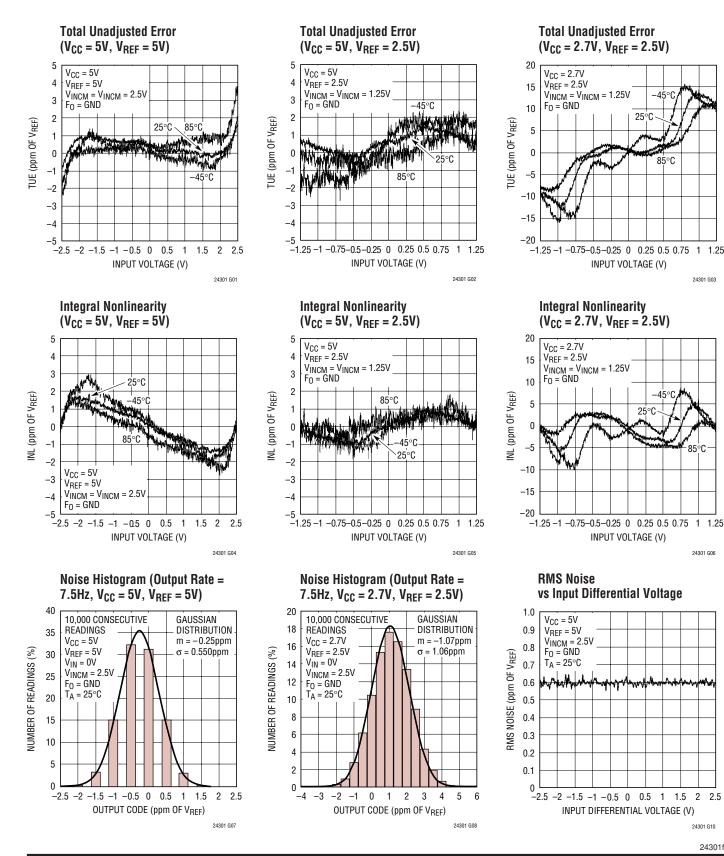
 $F_0 = 0V \text{ or } F_0 = V_{CC}.$ 

Note 13: The output noise includes the contribution of the internal calibration operations.

Note 14: Guaranteed by design and test correlation.

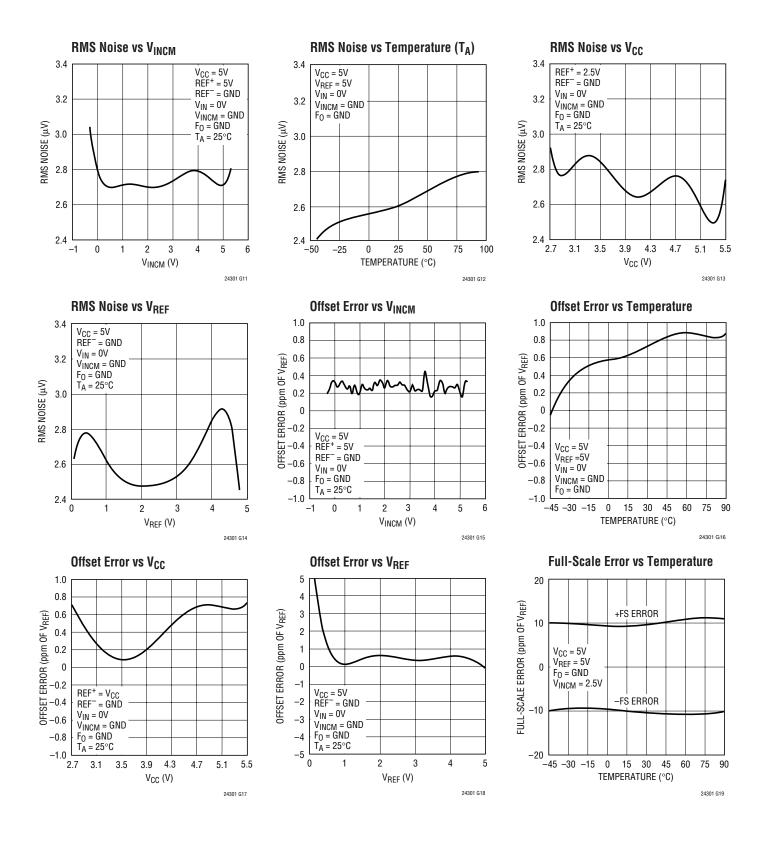


### TYPICAL PERFORMANCE CHARACTERISTICS



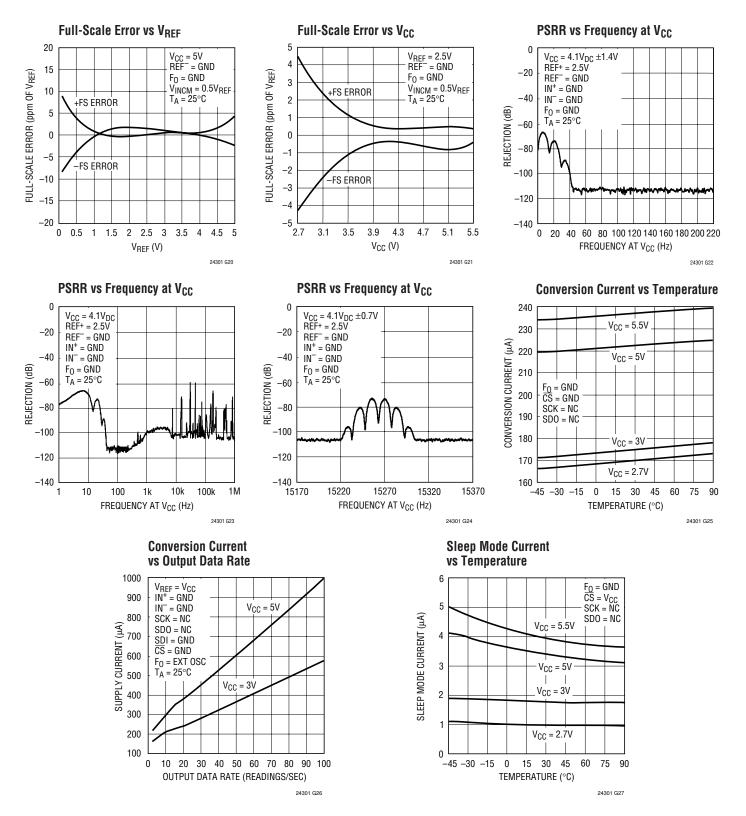


### **TYPICAL PERFORMANCE CHARACTERISTICS**





### TYPICAL PERFORMANCE CHARACTERISTICS





### PIN FUNCTIONS (LTC2430)

**GND (Pins 1, 7, 8, 9, 10, 15, 16):** Ground. Multiple ground pins internally connected for optimum ground current flow and  $V_{CC}$  decoupling. Connect each one of these pins to a ground plane through a low impedance connection. All seven pins must be connected to ground for proper operation.

 $V_{CC}$  (Pin 2): Positive Supply Voltage. Bypass to GND with a 10 $\mu$ F tantalum capacitor in parallel with 0.1 $\mu$ F ceramic capacitor as close to the part as possible.

**REF<sup>+</sup> (Pin 3), REF<sup>-</sup> (Pin 4):** Differential Reference Input. The voltage on these pins can have any value between GND and  $V_{CC}$  as long as the reference positive input, REF<sup>+</sup>, is maintained more positive than the reference negative input, REF<sup>-</sup>, by at least 0.1V.

**IN<sup>+</sup> (Pin 5), IN<sup>-</sup> (Pin 6):** Differential Analog Input. The voltage on these pins can have any value between GND – 0.3V and V<sub>CC</sub> + 0.3V. Within these limits the converter bipolar input range ( $V_{IN} = IN^+ - IN^-$ ) extends from – 0.5 • ( $V_{REF}$ ) to 0.5 • ( $V_{REF}$ ). Outside this input range the converter produces unique overrange and underrange output codes.

**CS** (Pin 11): Active LOW Digital Input. A LOW on this pin enables the SDO digital output and wakes up the ADC. Following each conversion the ADC automatically enters the Sleep mode and remains in this low power state as long as CS is HIGH. A LOW-to-HIGH transition on CS during the Data Output transfer aborts the data transfer and starts a new conversion.

#### (LTC2431)

 $V_{CC}$  (Pin 1): Positive Supply Voltage. Bypass to GND (Pin 6) with a 10 $\mu$ F tantalum capacitor in parallel with 0.1 $\mu$ F ceramic capacitor as close to the part as possible.

**REF<sup>+</sup> (Pin 2), REF<sup>-</sup> (Pin 3):** Differential Reference Input. The voltage on these pins can have any value between GND and  $V_{CC}$  as long as the reference positive input, REF<sup>+</sup>, is maintained more positive than the reference negative input, REF<sup>-</sup>, by at least 0.1V.

**IN<sup>+</sup> (Pin 4), IN<sup>-</sup> (Pin 5):** Differential Analog Input. The voltage on these pins can have any value between GND - 0.3V and V<sub>CC</sub> + 0.3V. Within these limits, the converter bipolar input range (V<sub>IN</sub> = IN<sup>+</sup> - IN<sup>-</sup>) extends

**SDO (Pin 12):** Three-State Digital Output. During the Data Output period, this pin is used as serial data output. When the chip select  $\overline{CS}$  is HIGH ( $\overline{CS} = V_{CC}$ ) the SDO pin is in a high impedance state. During the Conversion and Sleep periods, this pin is used as the conversion status output. The conversion status can be observed by pulling  $\overline{CS}$  LOW.

**SCK (Pin 13):** Bidirectional Digital Clock Pin. In Internal Serial Clock Operation mode, SCK is used as digital output for the internal serial interface clock during the Data Output period. In External Serial Clock Operation mode, SCK is used as digital input for the external serial interface clock during the Data Output period. A weak internal pullup is automatically activated in Internal Serial Clock Operation mode. The Serial Clock Operation mode is determined by the logic level applied to the SCK pin at power up or during the most recent falling edge of CS.

**F**<sub>0</sub> (Pin 14): Frequency Control Pin. Digital input that controls the ADC's notch frequencies and conversion time. When the  $F_0$  pin is connected to  $V_{CC}$  ( $F_0 = V_{CC}$ ), the converter uses its internal oscillator and the digital filter first null is located at 50Hz. When the  $F_0$  pin is connected to GND ( $F_0 = OV$ ), the converter uses its internal oscillator and the digital filter first null is located at 60Hz. When  $F_0$  is driven by an external clock signal with a frequency  $f_{EOSC}$ , the converter uses this signal as its system clock and the digital filter first null is located at a frequency  $f_{EOSC}/2560$ .

from  $-0.5 \cdot (V_{REF})$  to  $0.5 \cdot (V_{REF})$ . Outside this input range, the converter produces unique overrange and underrange output codes.

**GND (Pin 6):** Ground. Connect this pin to a ground plane through a low impedance connection.

**CS** (Pin 7): Active LOW Digital Input. A LOW on this pin enables the SDO digital output and wakes up the ADC. Following each conversion, the ADC automatically enters the Sleep mode and remains in this low power state as long as CS is HIGH. A LOW-to-HIGH transition on CS during the Data Output transfer aborts the data transfer and starts a new conversion.



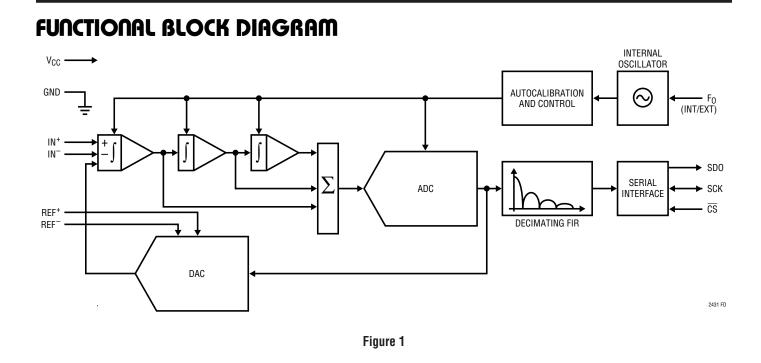
24301

### PIN FUNCTIONS (LTC2431)

**SDO** (Pin 8): Three-State Digital Output. During the Data Output period, this pin is used as the serial data output. When the chip select  $\overline{CS}$  is HIGH ( $\overline{CS} = V_{CC}$ ), the SDO pin is in a high impedance state. During the Conversion and Sleep periods, this pin is used as the conversion status output. The conversion status can be observed by pulling  $\overline{CS}$  LOW.

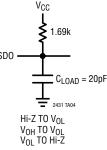
**SCK (Pin 9):** Bidirectional Digital Clock Pin. In Internal Serial Clock Operation mode, SCK is used as the digital output for the internal serial interface clock during the Data Output period. In External Serial Clock Operation mode, SCK is used as the digital input for the external serial interface clock during the Data Output period. A weak internal pull-up is automatically activated in Internal Serial Clock Operation mode. The Serial Clock Operation mode is determined by the logic level applied to the SCK pin at power up or during the most recent falling edge of  $\overline{CS}$ .

**F**<sub>0</sub> (Pin 10): Frequency Control Pin. Digital input that controls the ADC's notch frequencies and conversion time. When the F<sub>0</sub> pin is connected to V<sub>CC</sub> (F<sub>0</sub> = V<sub>CC</sub>), the converter uses its internal oscillator and the digital filter first null is located at 50Hz. When the F<sub>0</sub> pin is connected to GND (F<sub>0</sub> = OV), the converter uses its internal oscillator and the digital filter first null is located at 60Hz. When F<sub>0</sub> is driven by an external clock signal with a frequency f<sub>EOSC</sub>, the converter uses this signal as its system clock and the digital filter first null is located at a frequency f<sub>EOSC</sub>/2560.



# TEST CIRCUITS SDO $\underbrace{1.69k}_{Hi-Z TO V_{OH}} \underbrace{1.69k}_{2431 TA03} \underbrace{1.69k}_{Hi-Z TO V_{OH}} \underbrace{$

V<sub>OL</sub> TO V<sub>OH</sub> V<sub>OH</sub> TO Hi-Z





#### **CONVERTER OPERATION**

#### **Converter Operation Cycle**

The LTC2430/LTC2431 are low power, delta-sigma analogto-digital converters with an easy-to-use 3-wire serial interface (see Figure 1). Their operation is made up of three states. The converters' operating cycle begins with the conversion, followed by the low power sleep state and ends with the data output (see Figure 2). The 3-wire interface consists of serial data output (SDO), serial clock (SCK) and chip select ( $\overline{CS}$ ).

Initially, the LTC2430/LTC2431 perform a conversion. Once the conversion is complete, the device enters the sleep state. The part remains in the sleep state as long as  $\overline{CS}$  is HIGH. While in this sleep state, power consumption is reduced by nearly two orders of magnitude. The conversion result is held indefinitely in a static shift register while the converter is in the sleep state.

Once  $\overline{CS}$  is pulled LOW, the device exits the low power mode and enters the data output state. If  $\overline{CS}$  is pulled HIGH before the first rising edge of SCK, the device returns to the low power sleep mode and the conversion result is still held in the internal static shift register. If  $\overline{CS}$  remains LOW after the first rising edge of SCK, the device begins outputting the conversion result. Taking  $\overline{CS}$  high at this point will terminate the data output state and start a new conversion. There is no latency in the conversion result. The data output corresponds to the conversion just performed. This result is shifted out on the serial data out pin (SDO) under the control of the serial clock (SCK). Data is updated on the

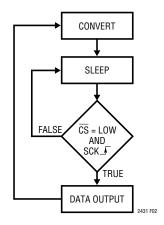


Figure 2. LTC2430/LTC2431 State Transition Diagram

falling edge of SCK allowing the user to reliably latch data on the rising edge of SCK (see Figure 3). The data output state is concluded once 24 bits are read out of the ADC or when  $\overline{CS}$  is brought HIGH. The device automatically initiates a new conversion and the cycle repeats.

Through timing control of the  $\overline{\text{CS}}$  and SCK pins, the LTC2430/LTC2431 offer several flexible modes of operation (internal or external SCK and free-running conversion modes). These various modes do not require programming configuration registers; moreover, they do not disturb the cyclic operation described above. These modes of operation are described in detail in the Serial Interface Timing Modes section.

#### **Conversion Clock**

A major advantage the delta-sigma converter offers over conventional type converters is an on-chip digital filter (commonly implemented as a Sinc or Comb filter). For high resolution, low frequency applications, this filter is typically designed to reject line frequencies of 50Hz or 60Hz plus their harmonics. The filter rejection performance is directly related to the accuracy of the converter system clock. The LTC2430/LTC2431 incorporate a highly accurate on-chip oscillator. This eliminates the need for external frequency setting components such as crystals or oscillators. Clocked by the on-chip oscillator, the LTC2430/ LTC2431 achieve a minimum of 110dB rejection at the line frequency (50Hz or 60Hz  $\pm 2\%$ ).

#### Ease of Use

The LTC2430/LTC2431 data output has no latency, filter settling delay or redundant data associated with the conversion cycle. There is a one-to-one correspondence between the conversion and the output data. Therefore, multiplexing multiple analog inputs is easy.

The LTC2430/LTC2431 perform offset and full-scale calibrations in every conversion cycle. This calibration is transparent to the user and has no effect on the cyclic operation described above. The advantage of continuous calibration is extreme stability of offset and full-scale readings with respect to time, supply voltage change and temperature drift.



#### Power-Up Sequence

The LTC2430/LTC2431 automatically enter an internal reset state when the power supply voltage  $V_{CC}$  drops below approximately 2V. This feature guarantees the integrity of the conversion result and of the serial interface mode selection. (See the 2-wire I/O sections in the Serial Interface Timing Modes section.)

When the V<sub>CC</sub> voltage rises above this critical threshold, the LTC2430 or LTC2431 creates an internal power-onreset (POR) signal with a duration of approximately 1ms. The POR signal clears all internal registers. Following the POR signal, the converter starts a normal conversion cycle and follows the succession of states described above. The first conversion result following POR is accurate within the specifications of the device if the power supply voltage is restored within the operating range (2.7V to 5.5V) before the end of the POR time interval.

#### **Reference Voltage Range**

The LTC2430/LTC2431 accept a differential external reference voltage. The absolute/common mode voltage specification for the REF<sup>+</sup> and REF<sup>-</sup> pins covers the entire range from GND to  $V_{CC}$ . For correct converter operation, the REF<sup>+</sup> pin must always be more positive than the REF<sup>-</sup> pin.

The LTC2430/LTC2431 can accept a differential reference voltage from 0.1V to  $V_{CC}$ . The converter (LTC2430 or LTC2431) output noise is determined by the thermal noise of the front-end circuits, and, as such, its value in microvolts is nearly constant with reference voltage. A decrease in reference voltage will not significantly improve the converter's effective resolution. On the other hand, a reduced reference voltage will improve the converter's overall INL performance. A reduced reference voltage will also improve the converter performance when operated with an external conversion clock (external F<sub>0</sub> signal) at substantially higher output data rates.

#### Input Voltage Range

The analog input is truly differential with an absolute/common mode range for the IN<sup>+</sup> and IN<sup>-</sup> input pins extending from GND - 0.3V to V<sub>CC</sub> + 0.3V. Outside these limits, the ESD protection devices begin to turn on and the errors due

to input leakage current increase rapidly. Within these limits, the LTC2430 or LTC2431 converts the bipolar differential input signal,  $V_{IN} = IN^+ - IN^-$ , from  $-FS = -0.5 \cdot V_{REF}$  to  $+FS = 0.5 \cdot V_{REF}$  where  $V_{REF} = REF^+ - REF^-$ . Outside this range the converter indicates the overrange or the underrange condition using distinct output codes.

Input signals applied to  $IN^+$  and  $IN^-$  pins may extend by 300mV below ground and above  $V_{CC}$ . In order to limit any fault current, resistors of up to 5k may be added in series with the  $IN^+$  and  $IN^-$  pins without affecting the performance of the device. In the physical layout, it is important to maintain the parasitic capacitance of the connection between these series resistors and the corresponding pins as low as possible; therefore, the resistors should be located as close as practical to the pins. In addition, series resistors will introduce a temperature dependent offset error due to the input leakage current. A 1nA input leakage current will develop a 1ppm offset error on a 5k resistor if  $V_{REF} = 5V$ . This error has a very strong temperature dependency.

#### **Output Data Format**

The LTC2430/LTC2431 serial output data stream is 24 bits long. The first 3 bits represent status information indicating the sign and conversion state. The next 21 bits are the conversion result, MSB first. The third and fourth bits together are also used to indicate an underrange condition (the differential input voltage is below -FS) or an overrange condition (the differential input voltage is above +FS).

Bit 23 (first output bit) is the end of conversion ( $\overline{EOC}$ ) indicator. This bit is available at the SDO pin during the conversion and sleep states whenever the  $\overline{CS}$  pin is LOW. This bit is HIGH during the conversion and goes LOW when the conversion is complete.

Bit 22 (second output bit) is a dummy bit (DMY) and is always LOW.

Bit 21 (third output bit) is the conversion result sign indicator (SIG). If V<sub>IN</sub> is >0, this bit is HIGH. If V<sub>IN</sub> is <0, this bit is LOW.

Bit 20 (fourth output bit) is the most significant bit (MSB) of the result. This bit in conjunction with Bit 21 also provides the underrange or overrange indication. If both Bit 21 and Bit 20 are HIGH, the differential input voltage is



above +FS. If both Bit 21 and Bit 20 are LOW, the differential input voltage is below –FS.

The function of these bits is summarized in Table 1.

Input Range	Bit 23 EOC	Bit 22 DMY	Bit 21 SIG	Bit 20 MSB
$V_{IN} \ge 0.5 \bullet V_{REF}$	0	0	1	1
$\overline{0V \le V_{IN} < 0.5 \bullet V_{REF}}$	0	0	1	0
$\overline{-0.5 \bullet V_{REF} \le V_{IN} < 0V}$	0	0	0	1
$V_{IN} < -0.5 \bullet V_{REF}$	0	0	0	0

#### Table 1. LTC2430/LTC2431 Status Bits

Bits 20-0 are the 21-bit conversion result MSB first.

Bit 0 is the least significant bit (LSB).

Data is shifted out of the SDO pin under control of the serial clock (SCK), see Figure 3. Whenever  $\overline{CS}$  is HIGH, SDO remains high impedance and any externally generated SCK clock pulses are ignored by the internal data out shift register.

In order to shift the conversion result out of the device,  $\overline{CS}$  must first be driven LOW. EOC is seen at the SDO pin of the device once  $\overline{CS}$  is pulled LOW. EOC changes real time from HIGH to LOW at the completion of a conversion. This signal may be used as an interrupt for an external microcontroller. Bit 23 (EOC) can be captured on the first rising edge of SCK. Bit 22 is shifted out of the device on the first falling edge of SCK. The final data bit (Bit 0) is shifted out on the falling edge of the 23rd SCK and may be latched on the rising edge of the 24th SCK pulse. On the falling edge of the 24th SCK pulse as EOC (Bit 22) for the next conversion cycle. Table 2 summarizes the output data format.

As long as the voltage on the IN<sup>+</sup> and IN<sup>-</sup> pins is maintained within the -0.3V to (V<sub>CC</sub> + 0.3V) absolute maximum operating range, a conversion result is generated for any differential input voltage V<sub>IN</sub> from  $-FS = -0.5 \cdot V_{REF}$  to  $+FS = 0.5 \cdot V_{REF}$ . For differential input voltages greater than

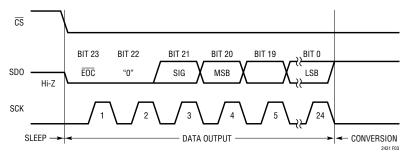


Figure 3. Output Data Timing

Differential Input Voltage V <sub>IN</sub> *	Bit 23 EOC	Bit 22 DMY	Bit 21 SIG	Bit 20 MSB	Bit 19	Bit 18	Bit 17	 Bit 0 LSB
$V_{IN}^* \ge 0.5 \bullet V_{REF}^{**}$	0	0	1	1	0	0	0	 0
0.5 • V <sub>REF</sub> ** – 1LSB	0	0	1	0	1	1	1	 1
0.25 • V <sub>REF</sub> **	0	0	1	0	1	0	0	 0
0.25 • V <sub>REF</sub> ** – 1LSB	0	0	1	0	0	1	1	 1
0	0	0	1	0	0	0	0	 0
-1LSB	0	0	0	1	1	1	1	 1
-0.25 • V <sub>REF</sub> **	0	0	0	1	1	0	0	 0
-0.25 • V <sub>REF</sub> ** - 1LSB	0	0	0	1	0	1	1	 1
−0.5 • V <sub>REF</sub> **	0	0	0	1	0	0	0	 0
V <sub>IN</sub> * < -0.5 • V <sub>REF</sub> **	0	0	0	0	1	1	1	 1

\*The differential input voltage  $V_{IN} = IN^+ - IN^-$ .

\*\*The differential reference voltage  $V_{REF} = REF^+ - REF^-$ .



+FS, the conversion result is clamped to the value corresponding to the +FS + 1LSB. For differential input voltages below -FS, the conversion result is clamped to the value corresponding to -FS - 1LSB.

### Frequency Rejection Selection (F<sub>0</sub>)

The LTC2430/LTC2431 internal oscillator provides better than 110dB normal mode rejection at the line frequency and all its harmonics for 50Hz  $\pm 2\%$  or 60Hz  $\pm 2\%$ . For 60Hz rejection, F<sub>0</sub> should be connected to GND while for 50Hz rejection the F<sub>0</sub> pin should be connected to V<sub>CC</sub>.

The selection of 50Hz or 60Hz rejection can also be made by driving  $F_0$  to an appropriate logic level. A selection change during the sleep or data output states will not disturb the converter operation. If the selection is made during the conversion state, the result of the conversion in progress may be outside specifications but the following conversions will not be affected.

When a fundamental rejection frequency different from 50Hz or 60Hz is required or when the converter must be synchronized with an outside source, the LTC2430 or LTC2431 can operate with an external conversion clock. The converter automatically detects the presence of an external clock signal at the  $F_0$  pin and turns off the internal oscillator. The frequency  $f_{EOSC}$  of the external signal must be at least 5kHz to be detected. The external clock signal duty cycle is not significant as long as the minimum and maximum specifications for the high and low periods  $t_{HEO}$  and  $t_{LEO}$  are observed.

While operating with an external conversion clock of a frequency  $f_{EOSC}$ , the LTC2430 or LTC2431 provides better than 110dB normal mode rejection in a frequency range  $f_{EOSC}/2560 \pm 4\%$  and its harmonics. The normal mode rejection as a function of the input frequency deviation from  $f_{EOSC}/2560$  is shown in Figure 4.

Whenever an external clock is not present at the  $F_0$  pin, the converter (LTC2430 or LTC2431) automatically activates its internal oscillator and enters the Internal Conversion Clock mode. Its operation will not be disturbed if the change of conversion clock source occurs during the sleep state or during the data output state while the converter uses an external serial clock. If the change occurs during the conversion state, the result of the conversion in

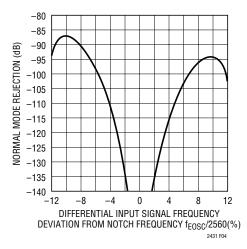


Figure 4. LTC2430/LTC2431 Normal Mode Rejection When Using an External Oscillator of Frequency  ${\rm f}_{\rm EOSC}$ 

progress may be outside specifications but the following conversions will not be affected. If the change occurs during the data output state and the converter is in the Internal SCK mode, the serial clock duty cycle may be affected but the serial data stream will remain valid.

Table 3 summarizes the duration of each state and the achievable output data rate as a function of  ${\rm F}_{\rm O}.$ 

#### SERIAL INTERFACE PINS

The LTC2430/LTC2431 transmit the conversion results and receives the start of conversion command through a synchronous 3-wire interface. During the conversion and sleep states, this interface can be used to assess the converter status and during the data output state it is used to read the conversion result.

#### Serial Clock Input/Output (SCK)

The serial clock signal present on SCK is used to synchronize the data transfer. Each bit of data is shifted out the SDO pin on the falling edge of the serial clock.

In the Internal SCK mode of operation, the SCK pin is an output and the converter (LTC2430 or LTC2431) creates its own serial clock by dividing the internal conversion clock by 8. In the External SCK mode of operation, the SCK pin is used as input. The internal or external SCK mode is selected on power-up and then reselected every time a HIGH-to-LOW transition is detected at the CS pin. If SCK





#### Table 3. LTC2430/LTC2431 State Duration

State	Operating Mode		Duration	
CONVERT	Internal Oscillator	F <sub>0</sub> = LOW (60Hz Rejection)	133ms, Output Data Rate $\leq$ 7.5 Readings/s	
		F <sub>0</sub> = HIGH (50Hz Rejection)	160ms, Output Data Rate $\leq$ 6.2 Readings/s	
	External Oscillator	F <sub>0</sub> = External Oscillator with Frequency f <sub>EOSC</sub> kHz (f <sub>EOSC</sub> /2560 Rejection)	20510/f <sub>EOSC</sub> s, Output Data Rate $\leq$ f <sub>EOSC</sub> /20510 Readings/s	
SLEEP			As Long As $\overline{CS}$ = HIGH	
DATA OUTPUT	Internal Serial Clock	F <sub>0</sub> = LOW/HIGH (Internal Oscillator)	As Long As $\overline{CS}$ = LOW But Not Longer Than 1.25ms (24 SCK cycles)	
		F <sub>0</sub> = External Oscillator with Frequency f <sub>EOSC</sub> kHz	As Long As $\overline{CS}$ = LOW But Not Longer Than 192/f <sub>EOSC</sub> ms (24 SCK cycles)	
	External Serial Clock with Frequency f <sub>SCK</sub> kHz		As Long As $\overline{CS}$ = LOW But Not Longer Than 24/f <sub>SCK</sub> ms (24 SCK cycles)	

is HIGH or floating at power-up or during this transition, the converter enters the internal SCK mode. If SCK is LOW at power-up or during this transition, the converter enters the external SCK mode.

#### Serial Data Output (SDO)

The serial data output pin, SDO, provides the result of the last conversion as a serial bit stream (MSB first) during the data output state. In addition, the SDO pin is used as an end of conversion indicator during the conversion and sleep states.

When  $\overline{\text{CS}}$  is HIGH, the SDO driver is switched to a high impedance state. This allows sharing the serial interface with other devices. If  $\overline{\text{CS}}$  is LOW during the convert or sleep state, SDO will output  $\overline{\text{EOC}}$ . If  $\overline{\text{CS}}$  is LOW during the conversion phase, the  $\overline{\text{EOC}}$  bit appears HIGH on the SDO pin. Once the conversion is complete,  $\overline{\text{EOC}}$  goes LOW.

#### Chip Select Input (CS)

The active LOW chip select,  $\overline{CS}$ , is used to test the conversion status and to enable the data output transfer as described in the previous sections.

In addition, the  $\overline{CS}$  signal can be used to trigger a new conversion cycle before the entire serial data transfer has been completed. The converter (LTC2430 or LTC2431) will abort any serial data transfer in progress and start a

new conversion cycle anytime a LOW-to-HIGH transition is detected at the  $\overline{CS}$  pin after the converter has entered the data output state (i.e., after the first rising edge of SCK occurs with  $\overline{CS}$  = LOW).

Finally,  $\overline{CS}$  can be used to control the free-running modes of operation, see Serial Interface Timing Modes section. Grounding  $\overline{CS}$  will force the ADC to continuously convert at the maximum output rate selected by  $F_0$ .

#### SERIAL INTERFACE TIMING MODES

The LTC2430/LTC2431's 3-wire interface is SPI and MICROWIRE compatible. This interface offers several flexible modes of operation. These include internal/external serial clock, 2- or 3-wire I/O, single cycle conversion. The following sections describe each of these serial interface timing modes in detail. In all these cases, the converter can use the internal oscillator ( $F_0 = LOW$  or  $F_0 = HIGH$ ) or an external oscillator connected to the  $F_0$  pin. Refer to Table 4 for a summary.

## External Serial Clock, Single Cycle Operation (SPI/MICROWIRE Compatible)

This timing mode uses an external serial clock to shift out the conversion result and a  $\overline{\text{CS}}$  signal to monitor and control the state of the conversion cycle, see Figure 5.

#### Table 4. LTC2430/LTC2431 Interface Timing Modes

Configuration	SCK Source	Conversion Cycle Control	Data Output Control	Connection and Waveforms
External SCK, Single Cycle Conversion	External	$\overline{\text{CS}}$ and SCK	CS and SCK	Figures 5, 6
External SCK, 2-Wire I/O	External	SCK	SCK	Figure 7
Internal SCK, Single Cycle Conversion	Internal	$\overline{\texttt{CS}}\downarrow$	$\overline{\texttt{CS}}\downarrow$	Figures 8, 9
Internal SCK, 2-Wire I/O, Continuous Conversion	Internal	Continuous	Internal	Figure 10

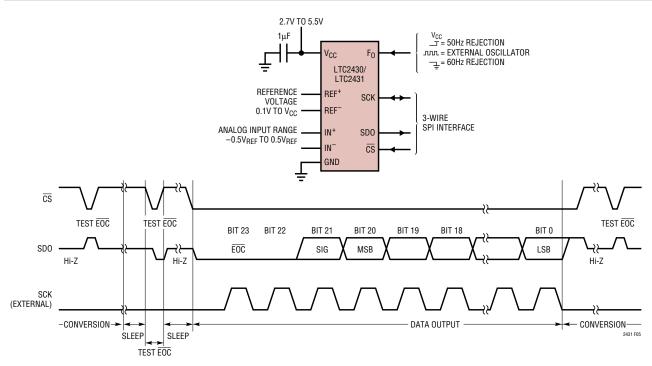


Figure 5. External Serial Clock, Single Cycle Operation

The serial clock mode is selected on the falling edge of  $\overline{CS}$ . To select the external serial clock mode, the serial clock pin (SCK) must be LOW during each  $\overline{CS}$  falling edge.

The serial data output pin (SDO) is Hi-Z as long as  $\overline{CS}$  is HIGH. At any time during the conversion cycle,  $\overline{CS}$  may be pulled LOW in order to monitor the state of the converter. While  $\overline{CS}$  is pulled LOW,  $\overline{EOC}$  is output to the SDO pin.  $\overline{EOC} = 1$  while a conversion is in progress and  $\overline{EOC} = 0$  if the conversion is over. With  $\overline{CS}$  HIGH, the device automatically enters the low power sleep state once the conversion is complete.

When  $\overline{\text{CS}}$  is low, the device enters the data output mode. The result is held in the internal static shift register until the first SCK rising edge is seen while  $\overline{\text{CS}}$  is LOW. Data is shifted out the SDO pin on each falling edge of SCK. This enables external circuitry to latch the output on the rising edge of SCK. EOC can be latched on the first rising edge of SCK and the last bit of the conversion result can be latched on the 24th rising edge of SCK. On the 24th falling edge of SCK, the device begins a new conversion. SDO goes HIGH (EOC = 1) indicating a conversion is in progress.

At the conclusion of the data cycle,  $\overline{\text{CS}}$  may remain LOW and  $\overline{\text{EOC}}$  monitored as an end-of-conversion interrupt. Alternatively,  $\overline{\text{CS}}$  may be driven HIGH setting SDO to Hi-Z. As described above,  $\overline{\text{CS}}$  may be pulled LOW at any time in order to monitor the conversion status.

Typically,  $\overline{\text{CS}}$  remains LOW during the data output state. However, the data output state may be aborted by pulling  $\overline{\text{CS}}$  HIGH anytime between the first rising edge and the 24th falling edge of SCK, see Figure 6. On the rising edge of  $\overline{\text{CS}}$ , <sup>24301f</sup>



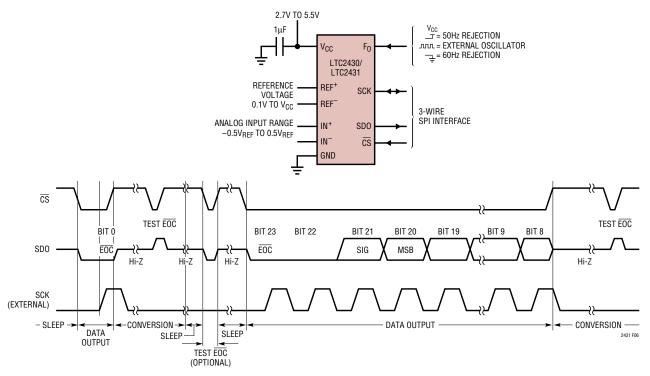


Figure 6. External Serial Clock, Reduced Data Output Length

the device aborts the data output state and immediately initiates a new conversion. This is useful for systems not requiring all 24 bits of output data, aborting an invalid conversion cycle or synchronizing the start of a conversion.

#### External Serial Clock, 2-Wire I/O

This timing mode utilizes a 2-wire serial I/O interface. The conversion result is shifted out of the device by an externally generated serial clock (SCK) signal, see Figure 7. CS may be permanently tied to ground, simplifying the user interface or isolation barrier.

The external serial clock mode is selected at the end of the power-on reset (POR) cycle. The POR cycle is concluded approximately 1ms after  $V_{CC}$  exceeds 2V. The level applied to SCK at this time determines if SCK is internal or external. SCK must be driven LOW prior to the end of POR in order to enter the external serial clock timing mode.

Since  $\overline{CS}$  is tied LOW, the end-of-conversion ( $\overline{EOC}$ ) can be continuously monitored at the SDO pin during the convert and sleep states.  $\overline{EOC}$  may be used as an interrupt to an external controller indicating the conversion result is ready.  $\overline{EOC} = 1$  while the conversion is in progress and  $\overline{\text{EOC}} = 0$  once the conversion ends. On the falling edge of  $\overline{\text{EOC}}$ , the conversion result is loaded into an internal static shift register. Data is shifted out the SDO pin on each falling edge of SCK enabling external circuitry to latch data on the rising edge of SCK.  $\overline{\text{EOC}}$  can be latched on the first rising edge of SCK. On the 24th falling edge of SCK, SDO goes HIGH ( $\overline{\text{EOC}} = 1$ ) indicating a new conversion has begun.

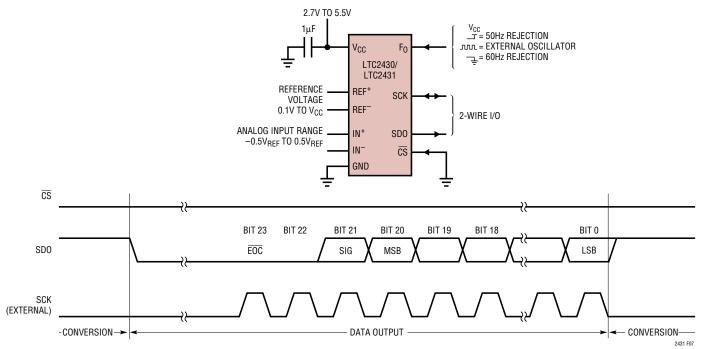
#### Internal Serial Clock, Single Cycle Operation

This timing mode uses an internal serial clock to shift out the conversion result and a  $\overline{CS}$  signal to monitor and control the state of the conversion cycle, see Figure 8.

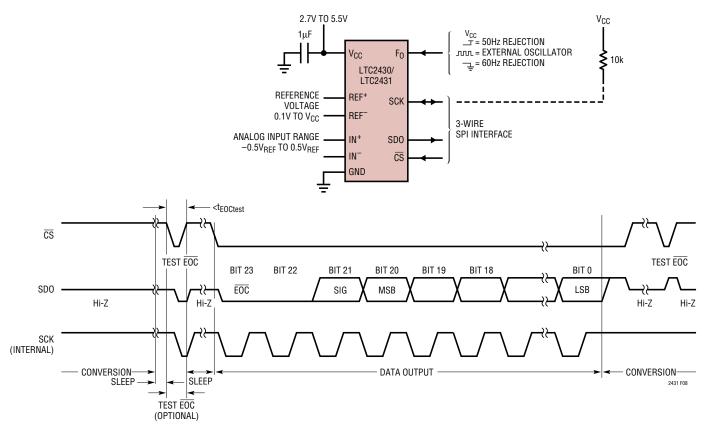
In order to select the internal serial clock timing mode, the serial clock pin (SCK) must be floating (Hi-Z) or pulled HIGH prior to the falling edge of  $\overline{CS}$ . The device will not enter the internal serial clock mode if SCK is driven LOW on the falling edge of  $\overline{CS}$ . An internal weak pull-up resistor is active on the SCK pin during the falling edge of  $\overline{CS}$ ; therefore, the internal serial clock timing mode is automatically selected if SCK is not externally driven.













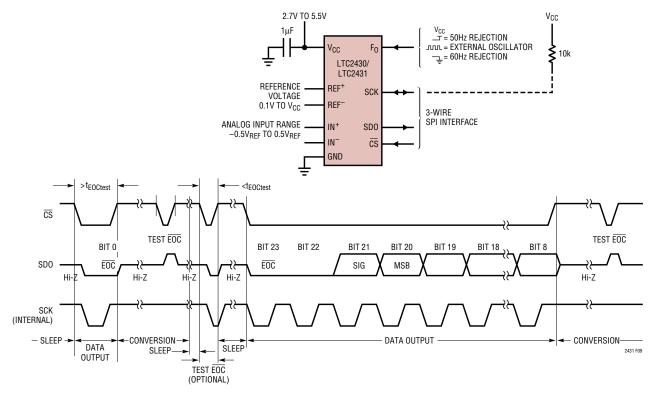


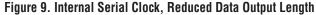
The serial data output pin (SDO) is Hi-Z as long as CS is HIGH. At any time during the conversion cycle,  $\overline{CS}$  may be pulled LOW in order to monitor the state of the converter. Once  $\overline{CS}$  is pulled LOW, SCK goes LOW and  $\overline{EOC}$  is output to the SDO pin.  $\overline{EOC} = 1$  while a conversion is in progress and  $\overline{EOC} = 0$  if the device is in the sleep state.

When testing EOC, if the conversion is complete (EOC = 0), the device will exit the sleep state and enter the data output state if CS remains LOW. In order to allow the device to return to the low power sleep state, CS must be pulled HIGH before the first rising edge of SCK. In the internal SCK timing mode, SCK goes HIGH and the device begins outputting data at time  $t_{EOCtest}$  after the falling edge of CS (if EOC = 0) or  $t_{EOCtest}$  after EOC goes LOW (if CS is LOW during the falling edge of EOC). The value of  $t_{EOCtest}$  is 23µs if the device is using its internal oscillator (F<sub>0</sub> = logic LOW or HIGH). If F<sub>0</sub> is driven by an external oscillator of frequency  $f_{EOSC}$ , then  $t_{EOCtest}$  is 3.6/ $f_{EOSC}$ . If CS is pulled HIGH before time  $t_{EOCtest}$ , the device returns to the sleep state. The conversion result is held in the internal static shift register.

If  $\overline{CS}$  remains LOW longer than  $t_{EOCtest}$ , the first rising edge of SCK will occur and the conversion result is serially shifted out of the SDO pin. The data output cycle begins on this first rising edge of SCK and concludes after the 24th rising edge. Data is shifted out the SDO pin on each falling edge of SCK. The internally generated serial clock is output to the SCK pin. This signal may be used to shift the conversion result into external circuitry. EOC can be latched on the first rising edge of SCK and the last bit of the conversion result on the 24th rising edge of SCK. After the 24th rising edge, SDO goes HIGH ( $\overline{EOC} = 1$ ), SCK stays HIGH and a new conversion starts.

Typically, CS remains LOW during the data output state. However, the data output state may be aborted by pulling CS HIGH anytime between the first and 24th rising edge of SCK, see Figure 9. On the rising edge of CS, the device aborts the data output state and immediately initiates a new conversion. This is useful for systems not requiring all 24 bits of output data, aborting an invalid conversion cycle, or synchronizing the start of a conversion. If CS is pulled HIGH while the converter is driving SCK LOW, the







internal pull-up is not available to restore SCK to a logic HIGH state. This will cause the device to exit the internal serial clock mode on the next falling edge of  $\overline{CS}$ . This can be avoided by adding an external 10k pull-up resistor to the SCK pin or by never pulling  $\overline{CS}$  HIGH when SCK is LOW.

Whenever SCK is LOW, the LTC2430/LTC2431's internal pull-up at pin SCK is disabled. Normally, SCK is not externally driven if the device is in the internal SCK timing mode. However, certain applications may require an external driver on SCK. If this driver goes Hi-Z after outputting a LOW signal, the LTC2430/LTC2431's internal pull-up remains disabled. Hence, SCK remains LOW. On the next falling edge of CS, the device is switched to the external SCK timing mode. By adding an external 10k pull-up resistor to SCK, this pin goes HIGH once the external driver goes Hi-Z. On the next CS falling edge, the device will remain in the internal SCK timing mode.

A similar situation may occur during the sleep state when  $\overline{CS}$  is pulsed HIGH-LOW-HIGH in order to test the conversion status. If the device is in the sleep state ( $\overline{EOC} = 0$ ), SCK will go LOW. Once  $\overline{CS}$  goes HIGH (within the time period defined above as  $t_{EOCtest}$ ), the internal pull-up is activated. For a heavy capacitive load on the SCK pin, the internal pull-up may not be adequate to return SCK to a

HIGH level before  $\overline{CS}$  goes low again. This is not a concern under normal conditions where  $\overline{CS}$  remains LOW after detecting  $\overline{EOC} = 0$ . This situation is easily overcome by adding an external 10k pull-up resistor to the SCK pin.

# Internal Serial Clock, 2-Wire I/O, Continuous Conversion

This timing mode uses a 2-wire, all output (SCK and SDO) interface. The conversion result is shifted out of the device by an internally generated serial clock (SCK) signal, see Figure 10.  $\overline{\text{CS}}$  may be permanently tied to ground, simplifying the user interface or isolation barrier.

The internal serial clock mode is selected at the end of the power-on reset (POR) cycle. The POR cycle is concluded approximately 1ms after  $V_{CC}$  exceeds 2V. An internal weak pull-up is active during the POR cycle; therefore, the internal serial clock timing mode is automatically selected if SCK is not externally driven LOW (if SCK is loaded such that the internal pull-up cannot pull the pin HIGH, the external SCK mode will be selected).

During the conversion, the SCK and the serial data output pin (SDO) are HIGH ( $\overline{EOC} = 1$ ). Once the conversion is complete, SCK and SDO go LOW ( $\overline{EOC} = 0$ ) indicating the conversion has finished and the device has entered the

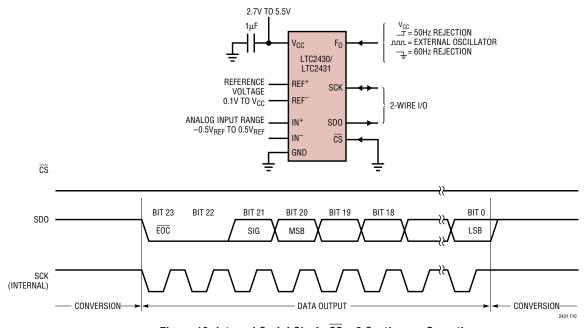


Figure 10. Internal Serial Clock,  $\overline{CS} = 0$  Continuous Operation





low power sleep state. The part remains in the sleep state a minimum amount of time (1/2 the internal SCK period) then immediately begins outputting data. The data output cycle begins on the first rising edge of SCK and ends after the 24th rising edge. Data is shifted out the SDO pin on each falling edge of SCK. The internally generated serial clock is output to the SCK pin. This signal may be used to shift the conversion result into external circuitry. EOC can be latched on the first rising edge of SCK and the last bit of the conversion result can be latched on the 24th rising edge of SCK. After the 24th rising edge, SDO goes HIGH (EOC = 1) indicating a new conversion is in progress. SCK remains HIGH during the conversion.

#### PRESERVING THE CONVERTER ACCURACY

The LTC2430/LTC2431 are designed to reduce as much as possible the conversion result sensitivity to device decoupling, PCB layout, antialiasing circuits, line frequency perturbations and so on. Nevertheless, in order to preserve the extreme accuracy capability of this part, some simple precautions are desirable.

#### **Digital Signal Levels**

The LTC2430/LTC2431's digital interface is easy to use. The digital inputs ( $F_0$ ,  $\overline{CS}$  and SCK in External SCK mode of operation) accept standard TTL/CMOS logic levels and the internal hysteresis receivers can tolerate edge rates as slow as 100 $\mu$ s. However, some considerations are required to take advantage of the exceptional accuracy and low supply current of this converter.

The digital output signals (SDO and SCK in Internal SCK mode of operation) are less of a concern because they are not generally active during the conversion state.

While a digital input signal is in the range 0.5V to  $(V_{CC} - 0.5V)$ , the CMOS input receiver draws additional current from the power supply. It should be noted that, when any one of the digital input signals (F<sub>0</sub>, CS and SCK in External SCK mode of operation) is within this range, the LTC2430/LTC2431 power supply current may increase even if the signal in question is at a valid logic level. For micropower operation, it is recommended to drive all digital input signals to full CMOS levels [V<sub>IL</sub> < 0.4V and V<sub>OH</sub> > (V<sub>CC</sub> - 0.4V)].

During the conversion period, the undershoot and/or overshoot of a fast digital signal connected to the LTC2430/ LTC2431 pins may severely disturb the analog to digital conversion process. Undershoot and overshoot can occur because of the impedance mismatch at the converter pin when the transition time of an external control signal is less than twice the propagation delay from the driver to LTC2430/LTC2431. For reference, on a regular FR-4 board, signal propagation velocity is approximately 183ps/inch for internal traces and 170ps/inch for surface traces. Thus, a driver generating a control signal with a minimum transition time of 1ns must be connected to the converter pin through a trace shorter than 2.5 inches. This problem becomes particularly difficult when shared control lines are used and multiple reflections may occur. The solution is to carefully terminate all transmission lines close to their characteristic impedance.

Parallel termination near the LTC2430/LTC2431 pin will eliminate this problem but will increase the driver power dissipation. A series resistor between  $27\Omega$  and  $56\Omega$ placed near the driver or near the LTC2431 pin will also eliminate this problem without additional power dissipation. The actual resistor value depends upon the trace impedance and connection topology.

An alternate solution is to reduce the edge rate of the control signals. It should be noted that using very slow edges will increase the converter power supply current during the transition time. The differential input and reference architecture reduce substantially the converter's sensitivity to ground currents.

Particular attention must be given to the connection of the  $F_0$  signal when the converter (LTC2430 or LTC2431) is used with an external conversion clock. This clock is active during the conversion time and the normal mode rejection provided by the internal digital filter is not very high at this frequency. A normal mode signal of this frequency at the converter reference terminals may result into DC gain and INL errors. A normal mode signal of this frequency at the converter input terminals may result into a DC offset error. Such perturbations may occur due to asymmetric capacitive coupling between the  $F_0$  signal trace and the converter input and/or reference connection traces. An immediate solution is to maintain maximum possible separation

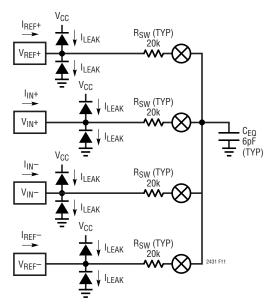


between the  $F_0$  signal trace and the input/reference signals. When the  $F_0$  signal is parallel terminated near the converter, substantial AC current is flowing in the loop formed by the  $F_0$  connection trace, the termination and the ground return path. Thus, perturbation signals may be inductively coupled into the converter input and/or reference. In this situation, the user must reduce to a minimum the loop area for the  $F_0$  signal as well as the loop area for the differential input and reference connections.

#### **Driving the Input and Reference**

The input and reference pins of the converter (LTC2430 or LTC2431) are directly connected to a network of sampling capacitors. Depending upon the relation between the differential input voltage and the differential reference voltage, these capacitors are switching between these four pins transfering small amounts of charge in the process. A simplified equivalent circuit is shown in Figure 11.

For a simple approximation, the source impedance  $R_S$  driving an analog input pin (IN<sup>+</sup>, IN<sup>-</sup>, REF<sup>+</sup> or REF<sup>-</sup>) can be considered to form, together with  $R_{SW}$  and  $C_{EQ}$  (see Figure 11), a first order passive network with a time constant  $\tau = (R_S + R_{SW}) \bullet C_{EQ}$ . The converter is able to



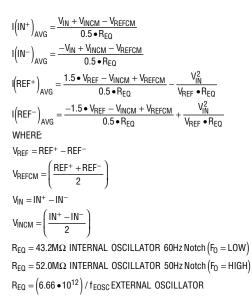
SWITCHING FREQUENCY  $f_{SW} = 76800 \text{Hz INTERNAL OSCILLATOR (F}_0 = \text{LOW OR HIGH)} \\ f_{SW} = 0.5 \bullet f_{EOSC} \text{EXTERNAL OSCILLATOR}$ 

sample the input signal with better than 1ppm accuracy if the sampling period is at least 14 times greater than the input circuit time constant  $\tau$ . The sampling process on the four input analog pins is quasi-independent so each time constant should be considered by itself and, under worst-case circumstances, the errors may add.

When using the internal oscillator (F<sub>0</sub> = LOW or HIGH), the LTC2430/LTC2431's front-end switched-capacitor network is clocked at 76800Hz corresponding to a 13µs sampling period. Thus, for settling errors of less than 1ppm, the driving source impedance should be chosen such that  $\tau \le 13\mu s/14 = 920ns$ . When an external oscillator of frequency f<sub>EOSC</sub> is used, the sampling period is 2/f<sub>EOSC</sub> and, for a settling error of less than 1ppm,  $\tau \le 0.14/f_{EOSC}$ .

#### **Input Current**

If complete settling occurs on the input, conversion results will be unaffected by the dynamic input current. An incomplete settling of the input signal sampling process may result in gain and offset errors, but it will not degrade the INL performance of the converter. Figure 11 shows the mathematical expressions for the average bias currents flowing through the IN<sup>+</sup> and IN<sup>-</sup> pins as a result of the







sampling charge transfers when integrated over a substantial time period (longer than 64 internal clock cycles).

The effect of this input dynamic current can be analyzed using the test circuit of Figure 12. The C<sub>PAR</sub> capacitor includes the LTC2430/LTC2431 pin capacitance (5pF typical) plus the capacitance of the test fixture used to obtain the results shown in Figures 13 and 14. A careful implementation can bring the total input capacitance (C<sub>IN</sub> + C<sub>PAR</sub>) closer to 5pF thus achieving better performance than the one predicted by Figures 13 and 14. For simplicity, two distinct situations can be considered.

For relatively small values of input capacitance ( $C_{IN}$  <  $0.01\mu$ F), the voltage on the sampling capacitor settles almost completely and relatively large values for the source impedance result in only small errors. Such values for CIN will deteriorate the converter offset and gain performance without significant benefits of signal filtering and the user is advised to avoid them. Nevertheless, when small values of C<sub>IN</sub> are unavoidably present as parasitics of input multiplexers, wires, connectors or sensors, the LTC2430 or LTC2431 can maintain its exceptional accuracy while operating with relative large values of source resistance as shown in Figures 13 and 14. These measured results may be slightly different from the first order approximation suggested earlier because they include the effect of the actual second order input network together with the nonlinear settling process of the input amplifiers. For small C<sub>IN</sub> values, the settling on IN<sup>+</sup> and IN<sup>-</sup> occurs almost independently and there is little benefit in trying to match the source impedance for the two pins.

Larger values of input capacitors ( $C_{IN} > 0.01\mu$ F) may be required in certain configurations for antialiasing or general input signal filtering. Such capacitors will average the input sampling charge and the external source resistance will see a quasi constant input differential impedance. When  $F_0 = LOW$  (internal oscillator and 60Hz notch), the typical differential input resistance is 21.6M $\Omega$  which will generate a gain error of approximately 0.023ppm for each ohm of source resistance driving IN<sup>+</sup> or IN<sup>-</sup>. When  $F_0 =$ HIGH (internal oscillator and 50Hz notch), the typical differential input resistance is 26M $\Omega$  which will generate a gain error of approximately 0.019ppm for each ohm of source resistance driving IN<sup>+</sup> or IN<sup>-</sup>. When  $F_0$  is driven by an external oscillator with a frequency  $f_{EOSC}$  (external conversion clock operation), the typical differential input resistance is  $3.3 \cdot 10^{12}/f_{EOSC}\Omega$  and each ohm of source resistance driving IN<sup>+</sup> or IN<sup>-</sup> will result in  $0.15 \cdot 10^{-6} \cdot f_{EOSC}$ ppm gain error. The effect of the source resistance on the two input pins is additive with respect to this gain error.

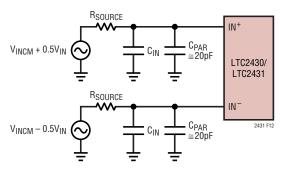


Figure 12. An RC Network at  $IN^+$  and  $IN^-$ 

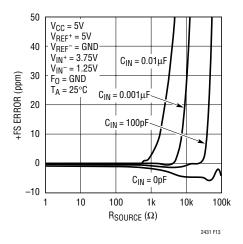


Figure 13. +FS Error vs  $R_{SOURCE}$  at IN<sup>+</sup> or IN<sup>-</sup> (Small C<sub>IN</sub>)

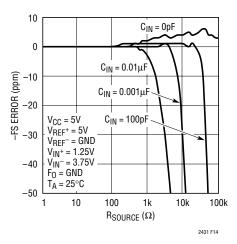


Figure 14. -FS Error vs R<sub>SOURCE</sub> at IN<sup>+</sup> or IN<sup>-</sup> (Small C<sub>IN</sub>)





The typical +FS and –FS errors as a function of the sum of the source resistance seen by  $IN^+$  and  $IN^-$  for large values of C<sub>IN</sub> are shown in Figure 15.

In addition to this gain error, an offset error term may also appear. The offset error is proportional with the mismatch between the source impedance driving the two input pins  $IN^+$  and  $IN^-$  and with the difference between the input and reference common mode voltages. While the input drive circuit nonzero source impedance combined with the converter average input current will not degrade the INL performance, indirect distortion may result from the modulation of the offset error by the common mode component of the input signal. Thus, when using large  $C_{IN}$  capacitor values, it is advisable to carefully match the source impedance seen by the  $IN^+$  and  $IN^-$  pins. When  $F_0 = LOW$ 

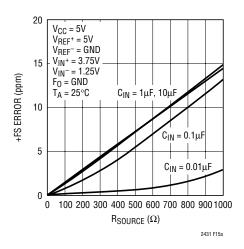


Figure 15a. +FS Error vs  $R_{SOURCE}$  at IN+ or IN- (Large  $C_{IN})$ 

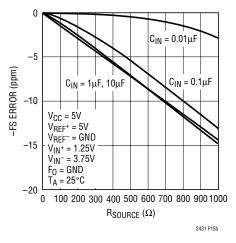


Figure 15b. – FS Error vs  $R_{SOURCE}$  at IN<sup>+</sup> or IN<sup>-</sup> (Large  $C_{IN}$ )

(internal oscillator and 60Hz notch), every 1 $\Omega$  mismatch in source impedance transforms a full-scale common mode input signal into a differential mode input signal of 0.023ppm. When F<sub>0</sub> = HIGH (internal oscillator and 50Hz notch), every 1 $\Omega$  mismatch in source impedance transforms a full-scale common mode input signal into a differential mode input signal of 0.019ppm. When F<sub>0</sub> is driven by an external oscillator with a frequency f<sub>EOSC</sub>, every 1 $\Omega$  mismatch in source impedance transforms a full-scale common mode input signal into a differential mode input signal of 0.15 • 10<sup>-6</sup> • f<sub>EOSC</sub>ppm. Figure 16 shows the typical offset error due to input common mode voltage for various values of source resistance imbalance between the IN<sup>+</sup> and IN<sup>-</sup> pins when large C<sub>IN</sub> values are used.

If possible, it is desirable to operate with the input signal common mode voltage very close to the reference signal common mode voltage as is the case in the ratiometric measurement of a symmetric bridge. This configuration eliminates the offset error caused by mismatched source impedances.

The magnitude of the dynamic input current depends upon the size of the very stable internal sampling capacitors and upon the accuracy of the converter sampling clock. The accuracy of the internal clock over the entire temperature and power supply range is typically better than 1%. Such

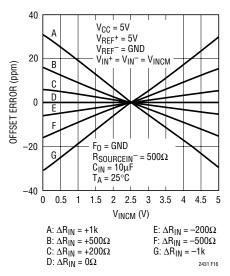


Figure 16. Offset Error vs Common Mode Voltage  $(V_{INCM} = V_{IN} + = V_{IN} -)$  and Input Source Resistance Imbalance  $(\Delta R_{IN} = R_{SOURCEIN} + - R_{SOURCEIN} -)$  for Large C<sub>IN</sub> Values (C<sub>IN</sub>  $\geq 1\mu F$ ) 243011



a specification can also be easily achieved by an external clock. When relatively stable resistors (50ppm/°C) are used for the external source impedance seen by  $IN^+$  and  $IN^-$ , the expected drift of the dynamic current, offset and gain errors will be insignificant (about 1% of their respective values over the entire temperature and voltage range). Even for the most stringent applications, a one-time calibration operation may be sufficient.

In addition to the input sampling charge, the input ESD protection diodes have a temperature dependent leakage current. This current, nominally 1nA ( $\pm$ 10nA max), results in a small offset shift. A 100 $\Omega$  source resistance will create a 0.1 $\mu$ V typical and 1 $\mu$ V maximum offset voltage.

#### **Reference Current**

In a similar fashion, the LTC2430 or LTC2431 samples the differential reference pins REF<sup>+</sup> and REF<sup>-</sup> transfering small amount of charge to and from the external driving circuits thus producing a dynamic reference current. This current does not change the converter offset, but it may degrade the gain and INL performance. The effect of this current can be analyzed in the same two distinct situations.

For relatively small values of the external reference capacitors ( $C_{REF} < 0.01 \mu F$ ), the voltage on the sampling capacitor settles almost completely and relatively large values for the source impedance result in only small errors. Such values for  $C_{REF}$  will deteriorate the converter offset and gain performance without significant benefits of reference filtering and the user is advised to avoid them.

Larger values of reference capacitors ( $C_{REF} > 0.01\mu$ F) may be required as reference filters in certain configurations. Such capacitors will average the reference sampling charge and the external source resistance will see a quasi constant reference differential impedance. When F<sub>0</sub> = LOW (internal oscillator and 60Hz notch), the typical differential reference resistance is 15.6M $\Omega$  which will generate a gain error of approximately 0.032ppm for each ohm of source resistance driving REF<sup>+</sup> or REF<sup>-</sup>. When F<sub>0</sub> = HIGH (internal oscillator and 50Hz notch), the typical differential reference resistance is 18.7M $\Omega$  which will generate a gain error of approximately 0.027ppm for each ohm of source resistance driving REF<sup>+</sup> or REF<sup>-</sup>. When F<sub>0</sub> is driven by an external oscillator with a frequency f<sub>EOSC</sub> (external conversion clock operation), the typical differential reference resistance is  $2.4 \cdot 10^{12}/f_{EOSC}\Omega$  and each ohm of source resistance drving REF<sup>+</sup> or REF<sup>-</sup> will result in 0.206  $\cdot 10^{-6} \cdot f_{EOSC}$ ppm gain error. The effect of the source resistance on the two reference pins is additive with respect to this gain error. The typical FS errors for various combinations of source resistance seen by the REF<sup>+</sup> and REF<sup>-</sup> pins and external capacitance C<sub>REF</sub> connected to these pins are shown in Figures 17 and 18. Typical–FS errors are similar to + FS errors with opposite polarity.

In addition to this gain error, the converter INL performance is degraded by the reference source impedance. When  $F_0 = LOW$  (internal oscillator and 60Hz notch), every 100 $\Omega$  of source resistance driving REF<sup>+</sup> or REF<sup>-</sup> translates

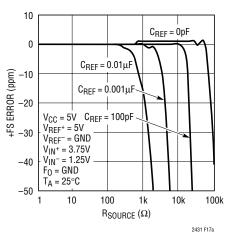


Figure 17a. +FS Error vs  $R_{SOURCE}$  at REF<sup>+</sup> or REF<sup>-</sup> (Small C<sub>IN</sub>)

